### **Features**

- Wide Power Supply Range, 3.0 V to 5.5 V
- Fast Read Access Time 150 ns
- Compatible with JEDEC Standard AT27C040
- Low Power 3.3-Volt CMOS Operation

20 μA max. Standby

29 mW max. Active at 5 MHz for Vcc = 3.6 V

- 138 mW max. Active at 5 MHz for V<sub>CC</sub> = 5.5 V 
   Wide Selection of JEDEC Standard Packages
  - 32-Lead 600-mil PDIP and Cerdip

32-Pad PLCC and LCC

32-Lead TSOP

- High Reliability CMOS Technology 2000 V ESD Protection 200 mA Latchup Immunity
- Rapid Programming 100 μs/byte (typical)
- Two-line Control
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Commercial and Industrial Temperature Ranges

### **Description**

The AT27LV040 chip is a low power, low voltage 4,194,304 bit ultraviolet erasable and electrically programmable read only memory (EPROM) organized as  $512K \times 8$  bits. It requires only one supply in the range of 3.0 to 5.5~V in normal read mode operation, making it ideal for portable systems.

With a typical power draw of only  $10\,\text{mW}$  at 1 MHz and  $V_{CC}$  at  $3.3\,\text{V}$ , the AT27LV040 draws less than one-fifth the power of a standard 5-V EPROM. Standby mode supply current is typically less than  $1\,\mu\text{A}$  at  $3.3\,\text{V}$ .

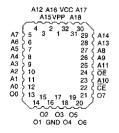
### **Pin Configurations**

Pin Name	Function
A0-A18	Addresses
00-07	Outputs
CE	Chip Enable
ŌE	Output Enable

### CDIP, PDIP, Top View

		~ ~		-	
VPP 🗆	1	_	32	Ь	VCC
A16 □	2		31	Ь	A18
A15 🗆	2		30	Þ	A17
A12 C	4		29	Þ	A14
A7 🗆	5		28	Þ	A13
A6 □	4 5 6		27	Þ	8A
A5 □	7		26	þ	A9
A4 🗆	8		29 28 27 26 25 24	Þ	A11
A3 U A2 U A1 U	9		24	Þ	ŌĒ
A2 🗆	10		23	Þ	A10
A1 🗆	11		22	Þ	A10 CE
A0 📮	12		21	Þ	07
00 ☐	13		20	Þ	06
01 📮	14		19	Þ	O5
A7 A6 A5 A4 A3 A2 A1 A0 O1 UU	13 14 15		18		04
GND 🗆	16		17	Þ	O3

#### LCC, PLCC Top View



### TSOP Top View

	i ype i				
A11 A9 0 0 1 A8 A9 0 0 1 A14 A13 0 0 4 5 A18 A17 0 0 6 7 VPP VCC 0 8 9 A15 A16 0 10 10 A7 A12 0 12 1	1	32 30 30 29 28 27 26 27 24 25 24 23 22 21	топринавания	A10 O7 O5 O3 O2 O0	OE CE O6 O4 GND
A7 A6 14 15	_	20 19 18 17	5	A1	A0 A2
A4 🖟 16		-17	Ъ.	АЗ	-



4 Megabit

 $(512K \times 8)$ 



### **Description** (Continued)

The AT27LV040 comes in a choice of industry standard JEDEC-approved packages, including: one-time programmable (OTP) plastic PDIP, PLCC, and TSOP, as well as windowed ceramic Cerdip and LCC. All devices feature two-line control  $(\overline{CE}, \overline{OE})$  to give designers the flexibility to prevent bus contention.

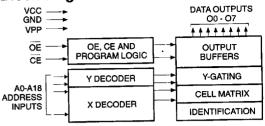
The AT27LV040 operating with  $V_{CC}$  at 3.0 V produces TTL level outputs that are compatible with standard TTL logic devices operating at  $V_{CC} = 5.0 \text{ V}$ .

Atmel's 27LV040 has additional features to ensure high quality and efficient production use. The Rapid Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100 µs/byte. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages. The AT27LV040 programs identically as an AT27C040.

### **Erasure Characteristics**

The entire memory array of the AT27LV040 is erased (all outputs read as VOH) after exposure to ultraviolet light at a wavelength of 2537 Å. Complete erasure is assured after a minimum of 20 minutes exposure using  $12,000~\mu\text{W/cm}^2$  intensity lamps spaced one inch away from the chip. Minimum erase time for lamps at other intensity ratings can be calculated from the minimum integrated erasure dose of 15 W-sec/cm². To prevent unintentional erasure, an opaque label is recommended to cover the clear window on any UV erasable EPROM which will be subjected to continuous fluorescent indoor lighting or sunlight.

### **Block Diagram**



### Absolute Maximum Ratings\*

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device.

This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied.

Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

#### Notes:

Minimum voltage is -0.6 V dc which may undershoot to -2.0
V for pulses of less than 20 ns. Maximum output pin voltage
is V<sub>CC</sub> + 0.75 V dc which may be exceeded if certain precautions are observed (consult application notes) and which may
overshoot to +7.0 V for pulses of less than 20 ns.

### **Operating Modes**

Mode \ Pin	CE	ŌĒ	Ai	VPP	Vcc	Outputs
Read	VIL	V <sub>IL</sub>	Ai	X <sup>(1)</sup>	Vcc	Dout
Output Disable	X	VIH	X	Х	Vcc	High Z
Standby	V <sub>IH</sub>	Х	X	Х	Vcc	High Z
Rapid Program <sup>(2)</sup>	ViL	ViH	Ai	VPP	Vcc (2)	DiN
PGM Verify <sup>(2)</sup>	X	VIL	Ai	V <sub>PP</sub>	Vcc (2)	Роит
PGM Inhibit <sup>(2)</sup>	VIH	ViH	X	VPP	Vcc (2)	High Z
Product Identification <sup>(2,4)</sup>	VIL	VIL	A9=V <sub>H</sub> <sup>(3)</sup> A0=V <sub>IH</sub> or V <sub>IL</sub> A1-A18=V <sub>IL</sub>	Х	Vcc <sup>(2)</sup>	Identification Code

Notes: 1. X can be  $V_{IL}$  or  $V_{IH}$ .

- Refer to Programming characteristics. Programming modes require V<sub>CC</sub> ≥ 4.5 V.
- 3.  $V_H = 12.0 \pm 0.5 \text{ V}$ .

4. Two identifier bytes may be selected. All Ai inputs are held low (V<sub>IL</sub>), except A9 which is set to V<sub>H</sub> and A0 which is toggled low (V<sub>IL</sub>) to select the Manufacturer's Identification byte and high (V<sub>IH</sub>) to select the Device Code byte.

## D.C. and A.C. Operating Conditions for Read Operation

		AT27LV040				
		-15	-20	-25		
Operating Temperature	Com.	0°C - 70°C	0°C - 70°C	0°C - 70°C		
(Case)	Ind.	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C		
Vcc Power Supply	<u> </u>	3.0 V to 5.5 V	3.0 V to 5.5 V	3.0 V to 5.5 V		

≃ Advance Information

# **D.C. and Operating Characteristics for Read Operation** (VCC = 3.0 V to 5.5 V unless otherwise specified)

Symbol	Parameter	Cond	ition		Min	Max	Units
ILI	Input Load Current	VIN =	0 V to Vcc	<del></del> .	******	±1	
ILO	Output Leakage Current		= 0 V to V <sub>CC</sub>			±5	μΑ
IPP1 (2)	VPP (1) Read/Standby Current	V <sub>PP</sub> =				10	μA
			CMOS), CE = V <sub>CC</sub> ± 0.3 V	V <sub>CC</sub> = 3	.6 V	20	μ <b>Α</b> μ <b>Α</b>
	Vcc (1) Standby Current	ISBY (CIVIOS), CE = VCC ± 0.3 V		V <sub>CC</sub> = 5	.5 V	100	μА
	•	Isaa (T	TTL), $\overline{CE} = 2.0 \text{ to V}_{CC} + 0.5 \text{ V}$	V <sub>CC</sub> = 3	.6 V	100	μА
				Vcc = 5	.5 V	1	mA
	Vcc Active Current	lcc1	$\underline{f} = 5 \text{ MHz}, \text{ lout} = 0 \text{ mA},$	Com.		8	mA
Icc			CE = V <sub>IL</sub> , V <sub>CC</sub> = 3.6 V	Ind.		10	mA
		lcc2	f = 5 MHz, lout = 0 mA	Com.		25	mA
			$\overline{CE} = V_{IL}, V_{CC} = 5.5 \text{ V}$	Ind.		30	mA
VIL	Input Low Voltage				-0.6	0.8	V
ViH	Input High Voltage			_	2.0	V <sub>CC+</sub> 0.5	V
VoL	Output Low Voltage	<u>lor = 5</u>	.0 mA			.4	V
	·	loL = 1	00 μΑ			.2	V
VOH	Output High Voltage	lон = -2.0 mA			2.4		V
		Юн = -	100 μΑ		/cc-0.2		V

Notes: 1.  $V_{CC}$  must be applied simultaneously or before  $V_{PP}$ , and removed simultaneously or after  $V_{PP}$ .

2. Vpp may be connected directly to  $V_{CC}$ , except during programming. The supply current would then be the sum of  $I_{CC}$  and  $I_{PP}$ .

## A.C. Characteristics for Read Operation (VCC = 3.0V to 5.5V)

						AT27	LV040			
					15	2	20	-2	25	
Symbol	Parameter	Condition		Min	Max	Min	Max	Min	Max	Units
tacc (3)	Address to Output Delay	CE = OE ≈ V <sub>IL</sub>	Com.		150		200		250	ns
(0)			Ind.		150		200		250	ns
tcE (2)	CE to Output Delay	OE = VIL			150		200		250	ns
toe (2,3)	OE to Output Delay	CE = VIL			60		70		100	ns
t <sub>DF</sub> <sup>(4,5)</sup>	OE or CE High to Output Float				50		50		50	ns
tон	Output Hold from Address, CE or OE, whichever occurred first			0		0		0		ns

Notes: 2, 3, 4, 5. - see AC Waveforms for Read Operation.

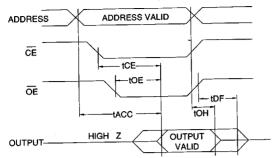


= Advance Information





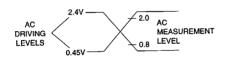
## A.C. Waveforms for Read Operation (1)



#### Notes:

- Timing measurement references are 0.8 V and 2.0 V. Input AC driving levels are 0.45 V and 2.4 V. See Input Test Waveforms and Measurement Levels.
- OE may be delayed up to t<sub>CE</sub>-t<sub>OE</sub> after the falling edge of CE without impact on t<sub>CE</sub>.
- OE may be delayed up to tACC-tOE after the address is valid without impact on tACC.
- 4. This parameter is only sampled and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.

## **Input Test Waveforms and Measurement Levels**



 $t_R$ ,  $t_F < 20$  ns (10% to 90%)

### **Output Test Load**



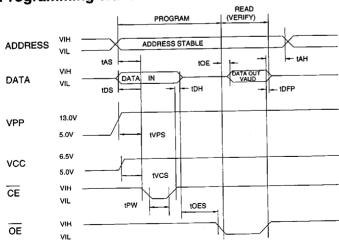
Note: C<sub>L</sub> = 100 pF including jig capacitance.

## Pin Capacitance $(f = 1 \text{ MHz}, T = 25^{\circ}\text{C})^{(1)}$

CIN	Тур			
	4	8	pF	V <sub>IN</sub> = 0 <u>V</u>
Cout	8	12	pF	V <sub>OUT</sub> = 0 V

Notes: 1. Typical values for 5-V supply voltage. This parameter is only sampled and is not 100% tested.

## Programming Waveforms (1)



#### Notes:

- 1. The Input Timing Reference is 0.8 V for V<sub>IL</sub> and 2.0 V for V<sub>IH</sub>.
- t<sub>OE</sub> and t<sub>DFP</sub> are characteristics of the device but must be accommodated by the programmer.
  - When programming the AT27LV040 a 0.1-µF capacitor is required across Vpp and ground to suppress spurious voltage transients.

AT27LV040

### **D.C. Programming Characteristics**

 $T_A = 25 \pm 5^{\circ}C$ ,  $V_{CC} = 6.5 \pm 0.25$  V,  $V_{PP} = 13.0 \pm 0.25$  V

Sym-		Test	Lir	mits	
bol	Parameter	Conditions	Min	Max	Units
ILI	Input Load Current	V <sub>IN</sub> =V <sub>IL</sub> ,V <sub>IH</sub>		10	μА
VIL	Input Low Level	(All Inputs)	-0.6	8.0	٧
ViH	Input High Level		2.0	Vcc+1	٧
Vol	Output Low Volt.	loL=2.1 mA		.45	٧
Voн	Output High Volt.	Іон≕-400 μА	2.4		٧
lcc2	Vcc Supply Curren (Program and Veri			40	mA
IPP2	V <sub>PP</sub> Supply Current	CE=V <sub>IL</sub>		20	mA
VID	A9 Product Identification Voltage		11.5	12.5	٧

### A.C. Programming Characteristics

 $T_A = 25 \pm 5^{\circ}C$ ,  $V_{CC} = 6.5 \pm 0.25 V$ ,  $V_{PP} = 13.0 \pm 0.25 V$ 

Sym- bol	Parameter	Test Conditions* (see Note 1)	<b>Li</b> r Min	nits Max l	Units
tas	Address Setup Tin	ne	2		μS
toes	OE Setup Time		2		μS
tos	Data Setup Time		2		μS
tan	Address Hold Time	9	0		μS
tDH	Data Hold Time		2		μS
topp	OE High to Output Float Delay	(Note 2)	0	130	ns
tvps	V <sub>PP</sub> Setup Time		2		μS
tvcs	V <sub>CC</sub> Setup Time		2		μS
tpw	CE Program Pulse Width	(Note 3)	95	105	μS
toe	Data Valid from OE	(Note 2)		150	ns

#### \*A.C. Conditions of Test:

Input Rise and Fall Times (10% to 90%)		20 ns
Input Pulse Levels	. 0.45	V to 2.4 V
Input Timing Reference Level	0.8	V to 2.0 V
Output Timing Reference Level	0.8	V to 2.0 V

#### Notes:

- V<sub>CC</sub> must be applied simultaneously or before V<sub>PP</sub> and removed simultaneously or after V<sub>PP</sub>.
- This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven — see timing diagram.
- Program Pulse width tolerance is 100 μsec ± 5%.

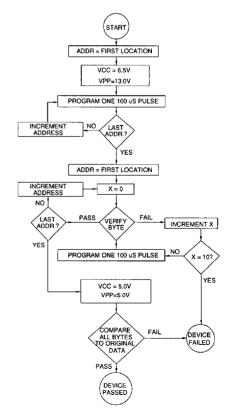
# Atmel's 27LV040 Integrated Product Identification Code

	Pins						Hex			
Codes	A0	07	O6	<b>O</b> 5	04	О3	<b>Q</b> 2	01	00	Data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device Type	1	0	0	0	0	1	0	1	1	ОВ

Note: 1. The AT27LV040 has the same Product Identification Code as the AT27C040. Both are programming compatible.

### **Rapid Programming Algorithm**

A 100  $\mu$ s  $\overline{\text{CE}}$  pulse width is used to program. The address is set to the first location.  $V_{CC}$  is raised to 6.5 V and Vpp is raised to 13.0 V. Each address is first programmed with one 100  $\mu$ s  $\overline{\text{CE}}$  pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100  $\mu$ s pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. Vpp is then lowered to 5.0 V and VcC to 5.0 V. All bytes are read again and compared with the original data to determine if the device passes or fails.







## **Ordering Information**

= Advance Information

tacc (ns)	Icc (mA) Vcc = 3.6 V Active Standby		Ordering Code	Package	Operation Range		
150	8	0.02	AT27LV040-15DC AT27LV040-15JC AT27LV040-15LC AT27LV040-15PC AT27LV040-15TC	32DW6 32J 32LW 32P6 32T	Commercial (0°C to 70°C)		
150	10	0.02	AT27LV040-15DI AT27LV040-15JI AT27LV040-15LI AT27LV040-15PI AT27LV040-15TI	32DW6 32J 32LW 32P6 32T	Industrial (-40°C to 85°C)		
200	8	0.02	AT27LV040-20DC AT27LV040-20JC AT27LV040-20LC AT27LV040-20PC AT27LV040-20TC	32DW6 32J 32LW 32P6 32T	Commercial (0°C to 70°C)		
200	10	0.02	AT27LV040-20DI AT27LV040-20JI AT27LV040-20LI AT27LV040-20PI AT27LV040-20TI	32DW6 32J 32LW 32P6 32T	Industrial (-40°C to 85°C)		
250	8	0.02	AT27LV040-25DC AT27LV040-25JC AT27LV040-25LC AT27LV040-25PC AT27LV040-25TC	32DW6 32J 32LW 32P6 32T	Commercial (0°C to 70°C)		
250	10	0.02	AT27LV040-25DI AT27LV040-25JI AT27LV040-25LI AT27LV040-25PI AT27LV040-25TI	32DW6 32J 32LW 32P6 32T	Industrial (-40°C to 85°C)		

	Package Type				
32DW6	32 Lead, 0.600" Wide, Windowed, Ceramic Dual Inline Package (Cerdip)				
32J	32 Lead, Plastic J-Leaded Chip Carrier OTP (PLCC)				
32LW	32 Pad, Windowed, Ceramic Leadless Chip Carrier (LCC)				
32P6	32 Lead, 0.600" Wide, Plastic Dual Inline Package OTP (PDIP)				
32T	32 Lead, Plastic Thin Small Outline Package OTP (TSOP)				